

CLAIMS

1. An ionization chamber for an ion source, said ionization chamber comprising an inert super alloy.
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2. An ionization chamber as recited in claim 1, wherein said inert super alloy is Inconel™ 625.
3. A system for analyzing a sample having constituents, said system comprising
10 an ion source having an ionization chamber with inward facing surfaces defining an interior volume, wherein said interior volume is exposed to said constituents and said ionization chamber comprises a substrate and an inward facing surface layer supported by said substrate, said layer comprising a super alloy.
- 15 4. An ionization chamber for an ion source, said ionization chamber having an inner surface comprising a conductive material selected from the group consisting of Inconel™ 625, Inconel™ 601, and Hastelloy®.
5. An ionization chamber as recited in claim 4, wherein said inner surface has a
20 resistivity lower than 0.001 ohm-cm.
6. An ionization chamber as recited in claim 4, wherein said inner surface is an outer surface of a coating.
- 25 7. An ionization chamber as recited in claim 4, additionally comprising a substrate positioned to support said inner surface.

8. An ionization chamber for an ion source, said ionization chamber having a coated inner surface for reduced interaction with reactive samples, wherein said coated inner surface comprises an abrasion-resistant Inconel™ 625 material of 5 thickness greater than 0.1 micron.

9. An ionization chamber as recited in claim 8, wherein said thickness is also less than about 10 microns.

10 10. A system for analyzing a sample having constituents, said system comprising an ion source having an ionization chamber with inward facing surfaces defining an interior volume, wherein said interior volume is exposed to said constituents and said ionization chamber comprises an electrically-conducting substrate and an inward facing surface layer supported by said substrate, said layer including an inert material 15 selected from the group consisting of Inconel™ 625, Inconel™ 601 and Hastelloy®.

11. A method of reducing interaction of a reactive analyte with a surface of an ion source, comprising applying a coating selected from the group consisting of Inconel™ 625, Inconel™ 601 and Hastelloy® to the surface.

20 12. A method of introducing a sample gas into an ionization chamber having inner surfaces of super alloy, comprising:
(a) ionizing a portion of said sample gas, thereby producing ions; and
(b) analyzing said ions with a mass-to-charge analyzer wherein within said 25 ionization chamber the sample gas is only exposed to said surfaces of said super alloy.